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(12) **United States Design Patent**
Teranishi et al.

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(54) **PROBE PIN**

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(**) Term: **15 Years**

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(52) **U.S. Cl.**
USPC **D10/80**

(58) **Field of Classification Search**

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CPC G01R 1/067; G01R 1/06705; G01R
1/06711; G01R 1/06716; G01R 1/06722;
G01R 1/06727; G01R 1/06733; G01R
1/06738; G01R 1/06744; G01R 1/0675;
G01R 1/06766; G01R 1/06772; G01R
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See application file for complete search history.

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(57) **CLAIM**

The ornamental design for a probe pin, as shown and
described.

DESCRIPTION

FIG. 1 is a top front perspective view of a probe pin showing
our new design;

FIG. 2 is a front view thereof;

FIG. 3 is a rear view thereof;

FIG. 4 is a left side view thereof;

FIG. 5 is a right side view thereof;

FIG. 6 is a top view thereof; and,

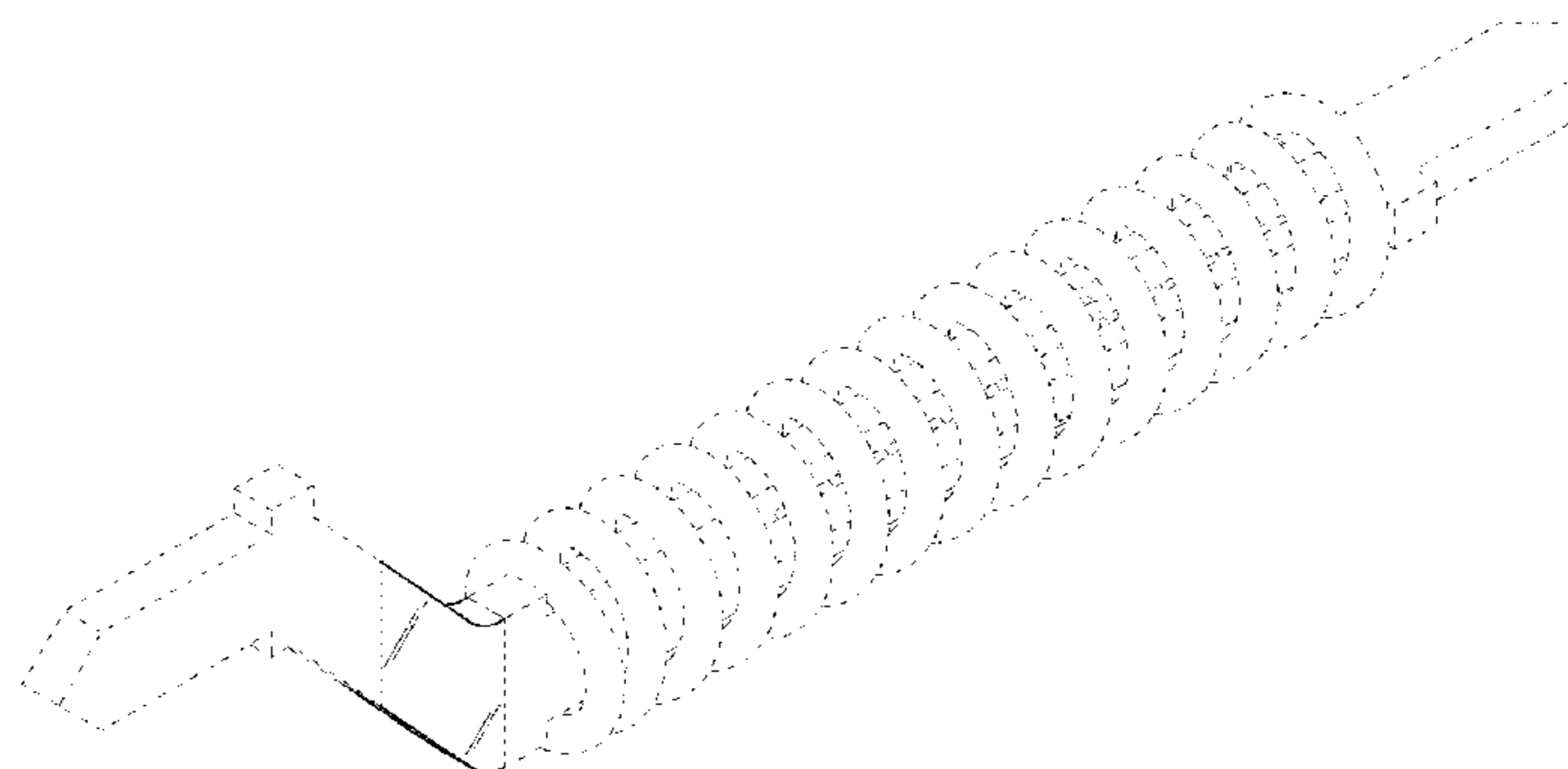
FIG. 7 is a bottom view thereof.

The dashed broken lines in the figures show portions of the
probe pin that form no part of the claimed design.

The dot-dash broken lines in the figures show boundaries of
the claimed design.

The shade lines in the figures show contour and not surface
ornamentation.

1 Claim, 4 Drawing Sheets



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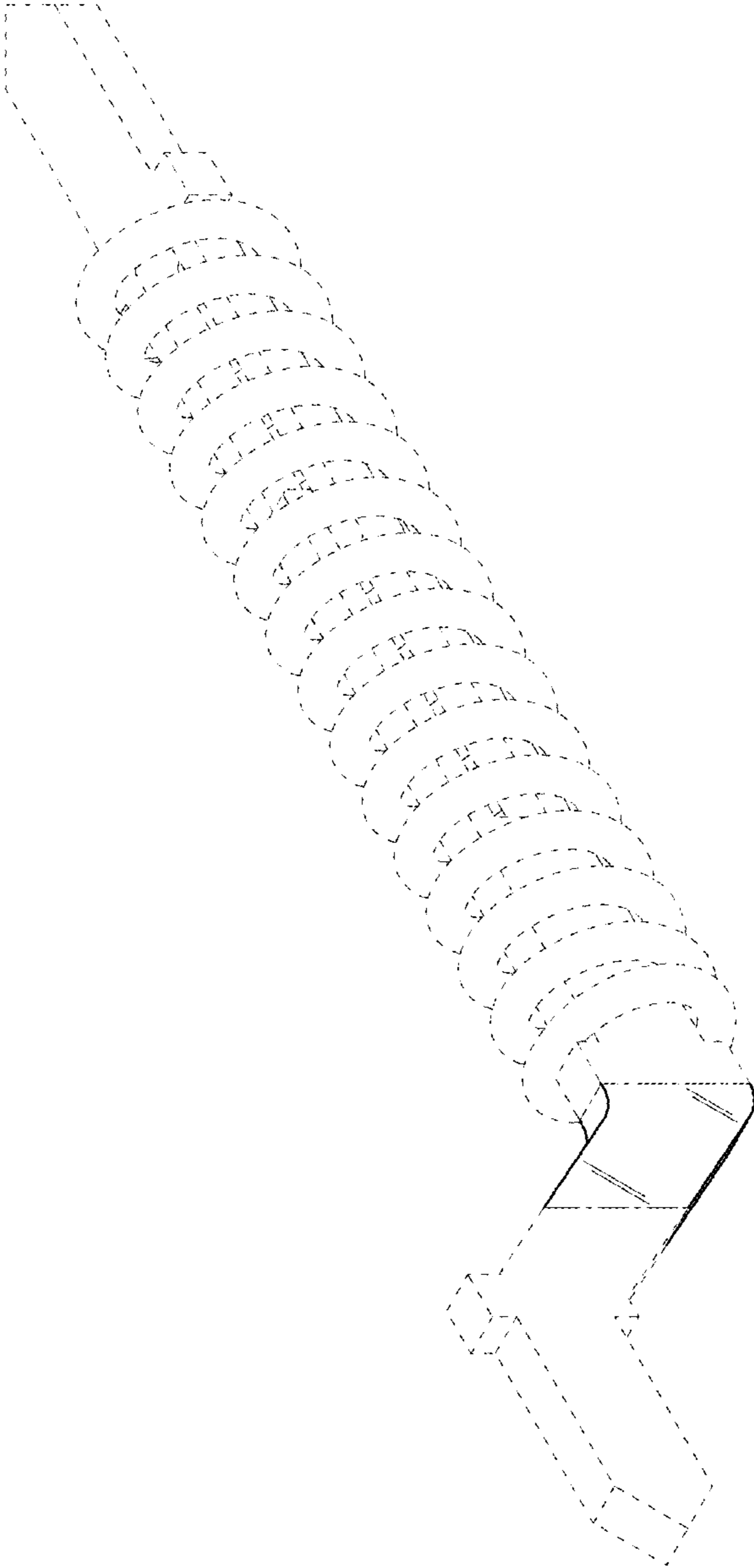


FIG. 1

FIG. 2

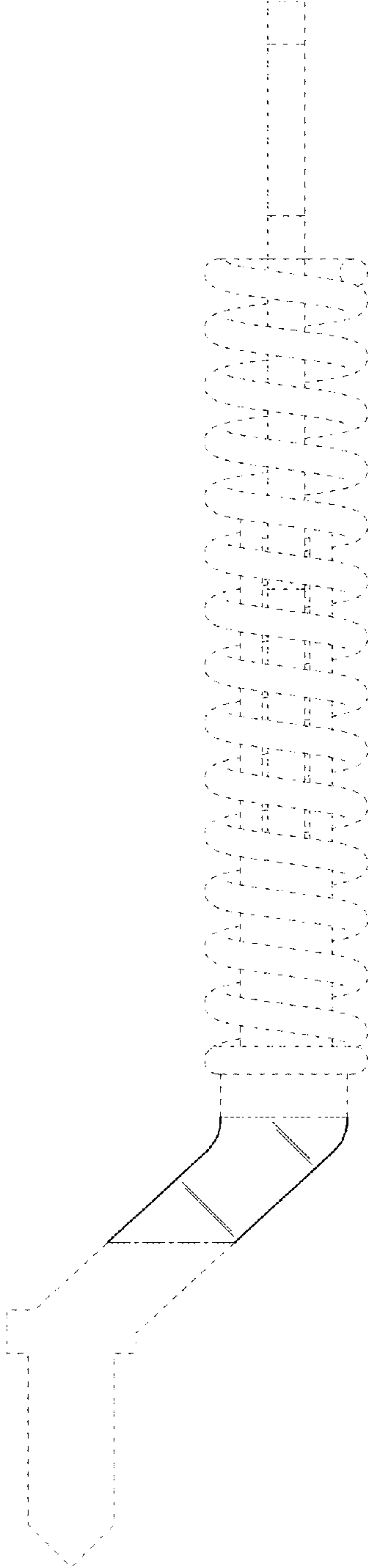
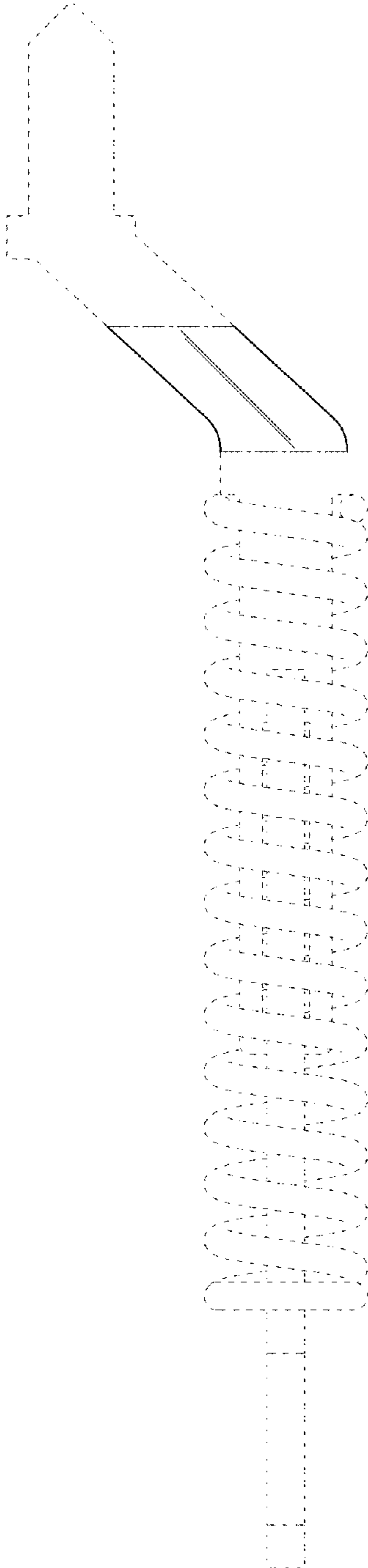


FIG. 3



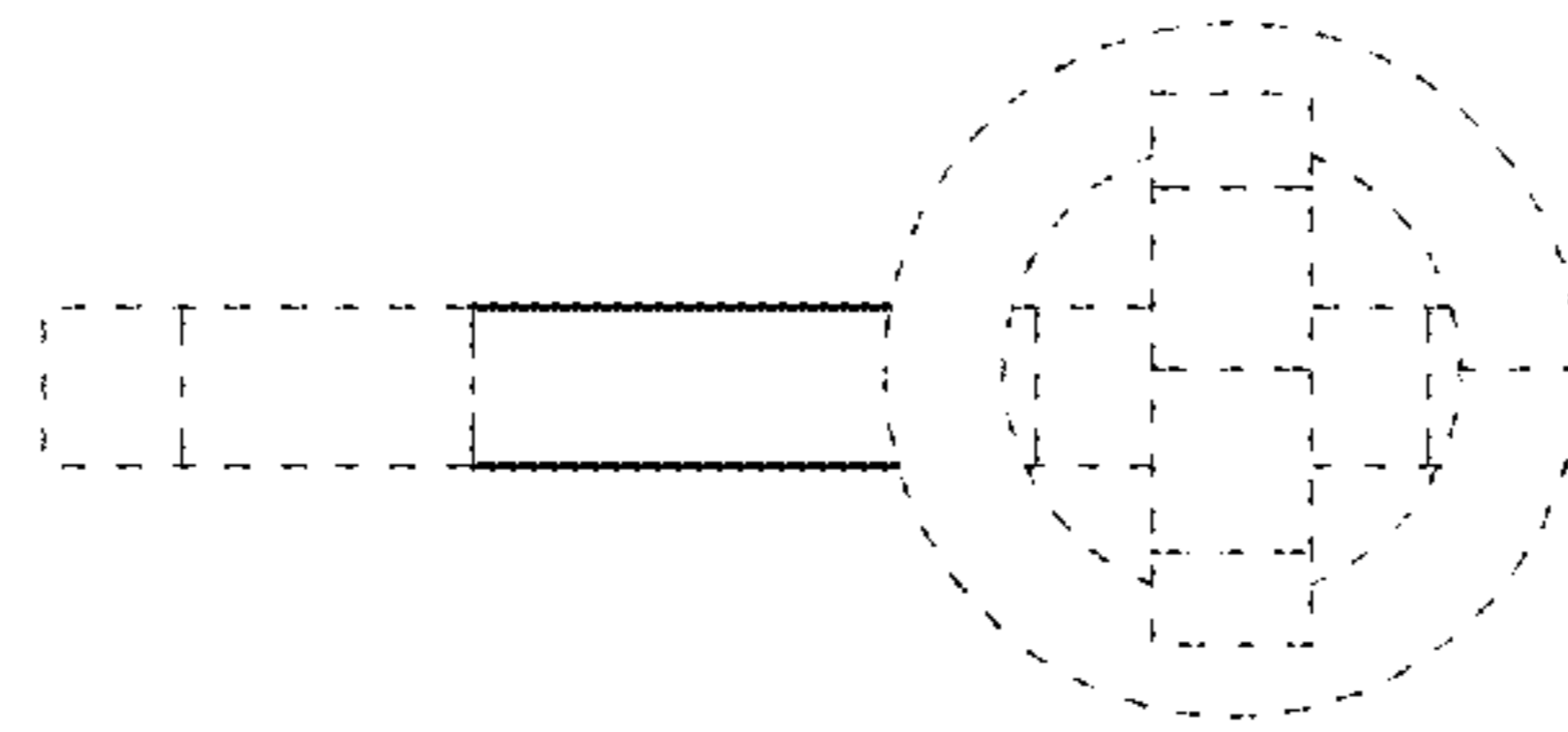


FIG. 5

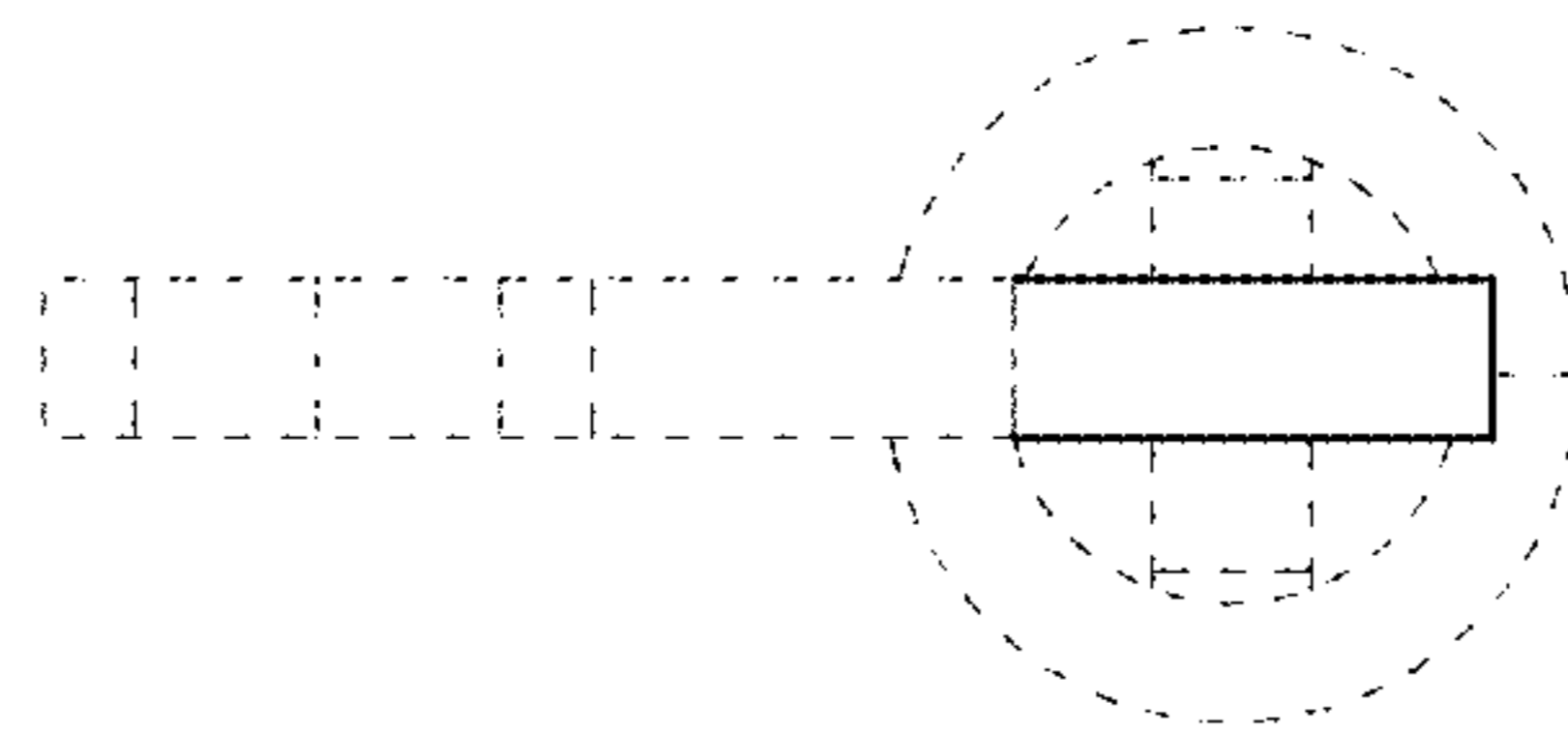


FIG. 4

FIG. 6

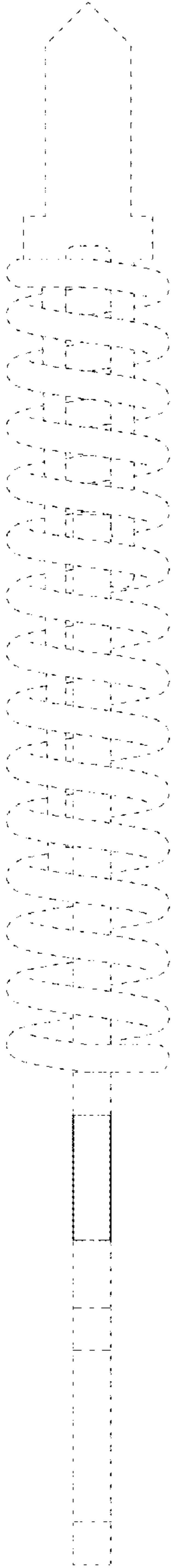


FIG. 7

